



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Paul B. Mirkarimi et al. Docket No. : CIL-10972
Serial No. : 10/086,614 Art Unit : 1762
Filed : March 1, 2002 Examiner : W. Markham
For : Ion-Assisted Deposition Techniques For
The Planarization Of Topological Defects

AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to the Office Action mailed April 21, 2006, please amend the
above-referenced application as follows: